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Build in Biasing Circuit MOS FET IC UHF RF Amplifier



ADE-208-700D (Z) 5th. Edition Mar. 2001

Features

- Build in Biasing Circuit; To reduce using parts cost & PC board space.
- High gain;

PG = 21.5 dB typ. at f = 900 MHz

• Low noise;

NF = 1.85 dB typ. at f = 900 MHz

• Withstanding to ESD;

Build in ESD absorbing diode. Withstand up to 200V at C=200pF, Rs=0 conditions.

• Provide mini mold packages; MPAK-4(SOT-143Rmod)

Outline

MPAK-4



- 1. Source
- 2. Gate1
- 3. Gate2
- 4. Drain

Notes: 1. Marking is "AS –".

2. BB501M is individual type number of HITACHI BBFET.

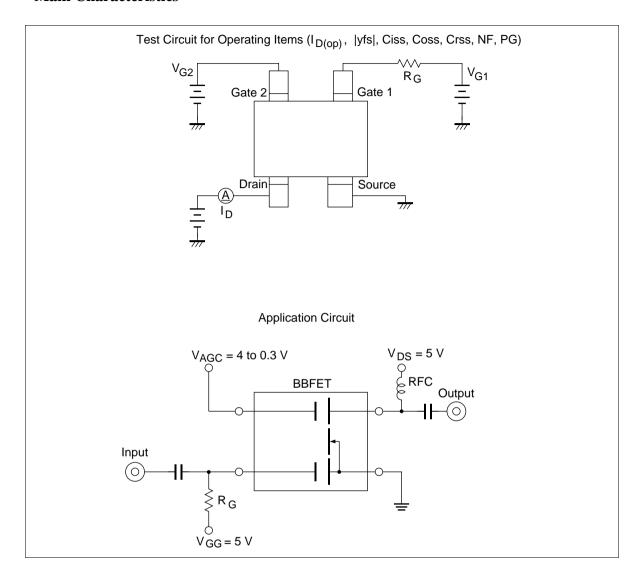
Absolute Maximum Ratings (Ta = 25°C)

Item	Symbol	Ratings	Unit	
Drain to source voltage	V _{DS}	6	V	
Gate1 to source voltage	$V_{\tt G1S}$	+6 - 0	V	
Gate2 to source voltage	V_{G2S}	+6 - 0	V	
Drain current	I _D	20	mA	
Channel power dissipation	Pch	150	mW	
Channel temperature	Tch	150	°C	
Storage temperature	Tstg	-55 to +150	°C	

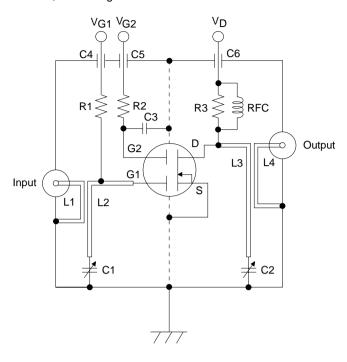
Electrical Characteristics ($Ta = 25^{\circ}C$)

Item	Symbol	Min	Тур	Max	Unit	Test Conditions
Drain to source breakdown voltage	$V_{(BR)DSS}$	6	_	_	V	$I_D = 200 \mu A$ $V_{G1S} = V_{G2S} = 0$
Gate1 to source breakdown voltage	$V_{(BR)G1SS}$	+6	_	_	V	$I_{G1} = +10 \mu A$ $V_{G2S} = V_{DS} = 0$
Gate2 to source breakdown voltage	$V_{(BR)G2SS}$	+6	_	_	V	$I_{G2} = +10 \mu A$ $V_{G1S} = V_{DS} = 0$
Gate1 to source cutoff current	I _{G1SS}	_	_	+100	nA	$V_{G1S} = +5V$ $V_{G2S} = V_{DS} = 0$
Gate2 to source cutoff current	I _{G2SS}	_	_	+100	nA	$V_{G2S} = +5V$ $V_{G1S} = V_{DS} = 0$
Gate1 to source cutoff voltage	$V_{G1S(off)}$	0.5	0.7	1.0	V	$V_{DS} = 5V, V_{G2S} = 4V$ $I_{D} = 100\mu A$
Gate2 to source cutoff voltage	$V_{\text{G2S(off)}}$	0.5	0.7	1.0	V	$V_{DS} = 5V, V_{G1S} = 5V$ $I_{D} = 100\mu A$
Drain current	I _{D(op)}	7	10	13	mA	$V_{DS} = 5V, V_{G1} = 5V$ $V_{G2S} = 4V, R_{G} = 47k\Omega$
Forward transfer admittance	y _{fs}	19	24	29	mS	$V_{DS} = 5V$, $V_{G1} = 5V$ $V_{G2S} = 4V$ $R_G = 47k\Omega$, $f = 1kHz$
Input capacitance	C _{iss}	1.4	1.7	2.0	pF	$V_{DS} = 5V, V_{G1} = 5V$
Output capacitance	C _{oss}	0.7	1.1	1.5	pF	$V_{G2S} = 4V, R_G = 47k\Omega$
Reverse transfer capacitance	C _{rss}	_	0.019	0.04	pF	f = 1MHz
Power gain	PG	17	21.5	_	dB	$V_{DS} = 5V, V_{G1} = 5V$ $V_{G2S} = 4V, R_{G} = 47k\Omega$
Noise figure	NF	_	1.85	2.4	dB	f = 900MHz

Main Characteristics



900MHz Power Gain, Noise Figure Test Circuit



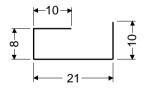
C1, C2: Variable Capacitor (10pF MAX)

C3: Disk Capacitor (1000pF)

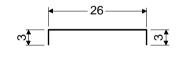
C4 to C6: Air Capacitor (1000pF)

 $\begin{array}{lll} \text{R1} : & 47 \text{ k}\Omega \\ \text{R2} : & 47 \text{ k}\Omega \\ \text{R3} : & 4.7 \text{ k}\Omega \end{array}$

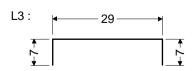
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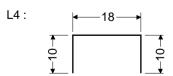


L2:

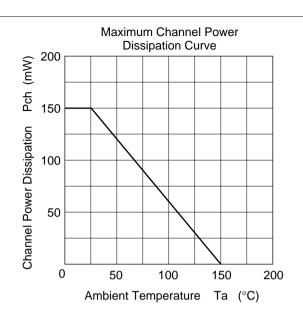


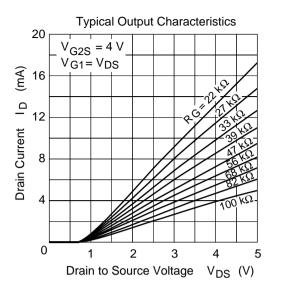
(\$\phi1mm Copper wire)
Unit: mm

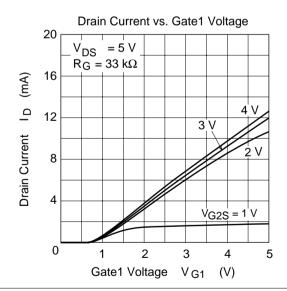


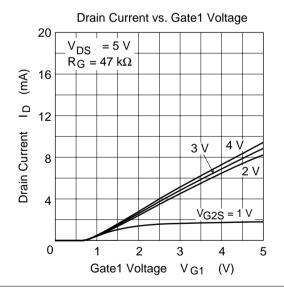


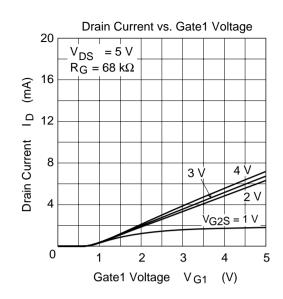
RFC: \$\phi1mm Copper wire with enamel 4turns inside dia 6mm

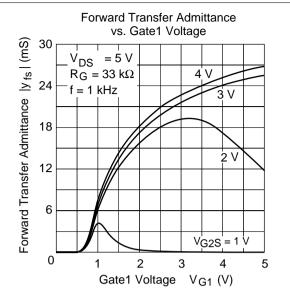


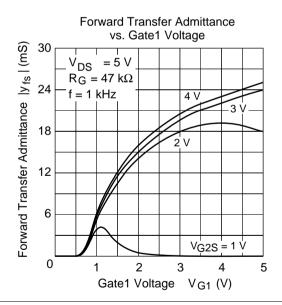


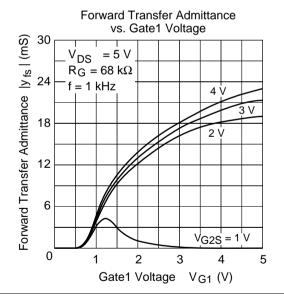


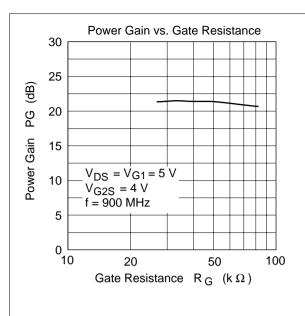


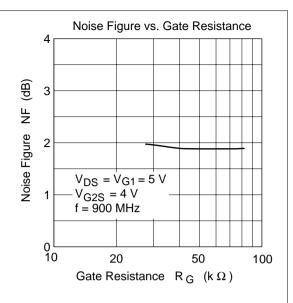


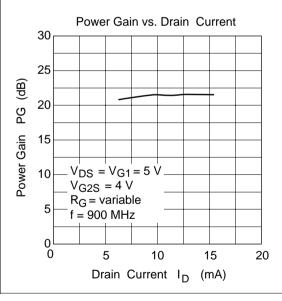


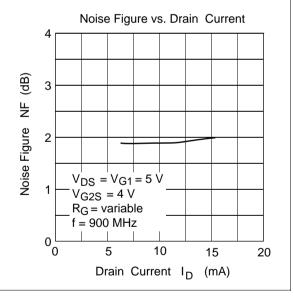


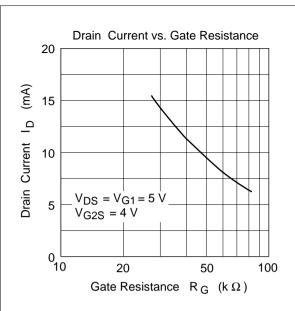


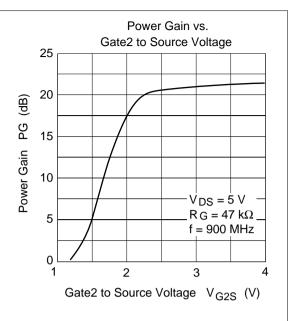


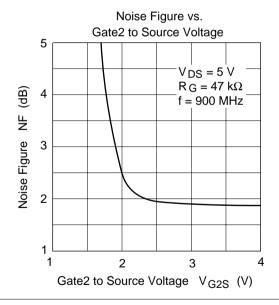


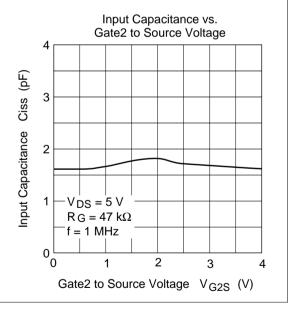


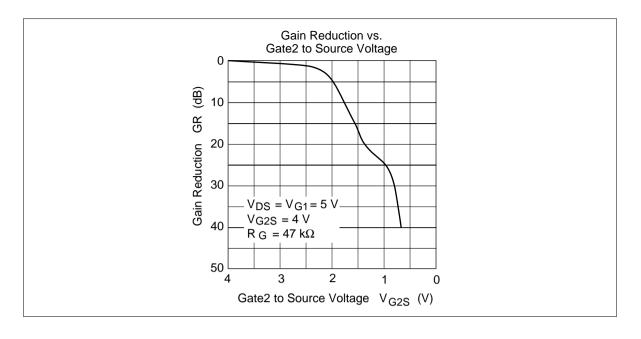






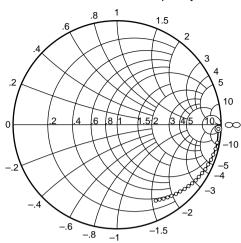






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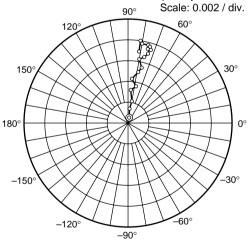
S11 Parameter vs. Frequency



Test Condition: V $_{DS}$ = 5 V , V $_{G1}$ = 5 V V_{G2S} = 4 V , R $_{G}$ = 47 k Ω , Zo = 50 Ω

50 to 1000 MHz (50 MHz step)

S12 Parameter vs. Frequency

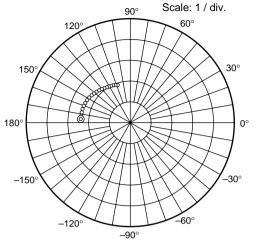


Test Condition: V $_{DS}$ = 5 V , V $_{G1}$ = 5 V V_{G2S} = 4 V , R $_{G}$ = 47 k Ω , Zo = 50 Ω

50 to 1000 MHz (50 MHz step)

⊚——

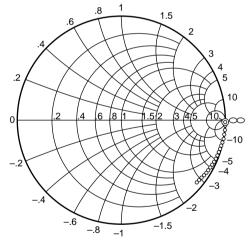
S21 Parameter vs. Frequency



Test Condition: V $_{DS}$ = 5 V , V $_{G1}$ = 5 V $_{VG2S}$ = 4 V , R $_{G}$ = 47 k Ω , $_{Z0}$ = 50 Ω

50 to 1000 MHz (50 MHz step)

S22 Parameter vs. Frequency



Test Condition: V $_{DS}$ = 5 V , V $_{G1}$ = 5 V V_{G2S} = 4 V , R $_{G}$ = 47 k Ω , Zo = 50 Ω

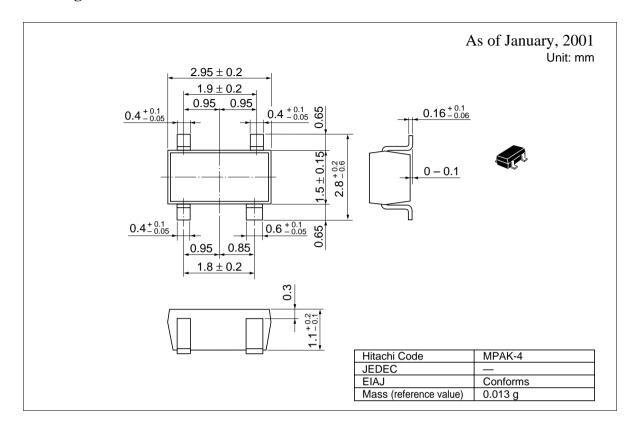
50 to 1000 MHz (50 MHz step)

⊚——

Sparameter	$(V_{DS} = V$	$V_{G1} = 5V, V_{G2}$	$_{\rm S} = 4 \text{V}, \text{R}_{\rm G} =$	$=47k\Omega$, $Zo = 50\Omega$)
-------------------	---------------	-----------------------	--	----------------------------------

	S11		S21		S12		S22	
f (MHz)	MAG	ANG	MAG	ANG	MAG	ANG	MAG	ANG
50	0.974	-2.8	2.40	176.4	0.00057	78.1	0.997	-2.0
100	0.974	-10.0	2.38	172.2	0.00144	82.4	0.998	-4.2
150	0.974	-13.6	2.38	168.4	0.00211	78.7	0.997	-6.0
200	0.965	-16.5	2.37	164.1	0.00316	84.8	0.995	-8.1
250	0.963	-20.0	2.35	160.4	0.00358	76.3	0.994	-10.2
300	0.953	-23.7	2.32	156.8	0.00431	84.0	0.992	-12.2
350	0.947	-26.8	2.30	152.9	0.00503	79.0	0.990	-14.2
400	0.942	-29.6	2.28	148.6	0.00545	76.6	0.987	-16.2
450	0.929	-32.8	2.26	144.9	0.00630	80.3	0.984	-18.1
500	0.923	-35.4	2.21	141.2	0.00646	76.1	0.981	-20.2
550	0.912	-38.5	2.19	137.6	0.00693	73.7	0.977	-22.1
600	0.903	-41.2	2.15	134.2	0.00732	72.9	0.974	-24.1
650	0.886	-44.2	2.12	130.6	0.00729	74.6	0.971	-26.0
700	0.879	-46.8	2.08	127.4	0.00733	72.0	0.967	-27.8
750	0.873	-49.2	2.06	124.3	0.00762	74.5	0.962	-29.7
800	0.859	-52.4	2.03	120.8	0.00756	73.7	0.959	-31.7
850	0.846	-55.4	2.00	117.3	0.00772	75.5	0.955	-33.6
900	0.836	-58.0	1.96	114.3	0.00775	79.6	0.951	-35.5
950	0.827	-60.4	1.93	111.0	0.00801	81.7	0.946	-37.3
1000	0.815	-62.8	1.89	108.0	0.00704	81.0	0.942	-39.4

Package Dimensions



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